R esistive relaxation in eld-induced insulator-m etal transition of a $(La_{0.4}Pr_{0.6})_{1.2}Sr_{1.8}Mn_{2}O_{7}$ bilayer manganite single crystal

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We have investigated the resistive relaxation of a $(La_{0.4} P r_{0.6})_{1.2} S r_{1.9} M n_2 O_7$ single crystal, in order to exam ine the slow dynam ics of the eld-induced insulator to metal transition of bilayered manganites. The temporal proles observed in remanent resistance follow a stretched exponential function accompanied by a slow relaxation similar to that obtained in magnetization and magnetostriction data. We demonstrate that the remanent relaxation in magnetotransport has a close relationship with magnetic relaxation that can be understood in the framework of an elective medium approximation by assuming that the retorder parameter is proportional to the second order one.

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I. INTRODUCTION

The discovery of the colossal magnetoresistance (CMR) e ect in doped manganites with perovskite structure has stimulated considerable interest for the understanding of their physical properties. Though the insulator to metal (IM) transition and its associated CMR are well explained on the basis of the double exchange (DE) model, it is pointed out that the dynamic Jahn-Teller (JT) e ect due to the strong electron-phonon interaction, plays a signicant role in the appearance of CMR as well as the DE interaction. Furthermore, Dagotto et al: propose a phase separation model where ferrom agnetic (FM) metallic and antiferrom agnetic (AFM) insulating clusters coexist as supported by recent experimental studies on the physics of manganites.

The bilayer manganite La1:2Sr1:8M n2O7 exhibits a param agnetic insulator (PM I) to ferrom agnetic metal (FMM) transition around T_c 120K and its associated CMR e ect⁵. In comparison with cubic manganites, the MR e ect of the compound under consideration, due to its layered structure, is enhanced by two orders of magnitude, at 8T, around T_c . It is well known that Pr-substitution on the La-site leading to $(La_1 \ _z \ P \ r_z)_{1:2} S r_{1:8} M \ n_2 O \ _7$ causes an elongation of the c axis length in contrast with a shrinkage of the a (b) axis, resulting in a change of the ea-electron occupation from the $d_{x^2-y^{\,2}}$ to the $d_{3z^2-r^{\,2}}$ orbita $1^{\!6,7,8}$. These $\,$ ndings also accompany a variation of the easy axis of magnetization from the ab plane to the caxis. For the z=0.6 crystal, the eld-induced FMM state is realized, instead of the PM I ground state in the absence of magnetic eld. In Fig.1, a phase diagram in the (M;T) plane established from the magnetization measurements carried out on the z = 0.6 crystal, with three regions labeled as the PM I, FMM and mixed phases (hatched area) is presented 10 .

A schematic diagram of free energy with two local minim a corresponding to the PMI and FMM states is also given in Fig.1, for the virgin state (a) before application of the magnetic eld, the eld-induced state (b) after the PM I to FM M transition and the mixed state (c) after rem oval of the eld. Just after rem oving the eld, the system still remains in a metastable FMM state. After a long time, the system comes back to the original PM I state through the mixed state consisting of both FMM and PMI regions. In the mixed state, the total system is divided into a large number of subsystems which are random by distributed with dierent local densities of free energy, causing complex relaxation processes observed in the physical property studies 11,12,13,14,15,16 . A magnetic frustration between double-exchange ferrom agnetic and superexchange antiferrom agnetic interactions at the M n sites gives rise to a spin-glass-like behavior in manganites 12,13,15. In the mixed phase composed of metallic and insulating regions, it is believed that the resistive relaxations reported 11,14 arise from an electronic com petition between double-exchange like itinerancy and carrier localization associated with the formation of polarons. Recently, the slow dynamics of a rem anent lattice striction of (La_{0:4}Pr_{0:6})_{1:2}Sr_{1:8}M n₂O₇ single crystal has been exam ined on the basis of a com petition between Jahn-Teller type orbital-lattice and DE interactions¹⁶. The form er interaction induces a local lattice distortion of M n O 6 octahedra along the c-axis but the latter suppresses a lattice deformation through the itinerant state¹⁷. Thus, it is desirable to establish a close relationship among the resistive, magnetic and lattice relaxations, for our understanding of the CMR phenomena in bilayered manganites.

Hence, we have investigated the resistive relaxation of a $(La_{0.4}Pr_{0.6})_{1.2}Sr_{1.8}Mn_2O_7$ single crystal. We compare our results with both magnetic and lattice relaxation data on the z=0.6 crystal.

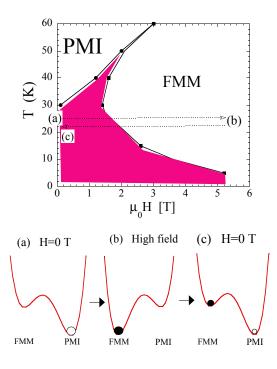


FIG. 1: Magnetic phase diagram in the (H;T) plane established from the magnetic measurements carried out on the z=0.6 crystal. A schematic picture of the free energy with two local minima corresponding to the FMM and PMI phases (regions (a), (b) and (c) correspond to virgin state, eld-induced metallic state and mixed state, respectively.)

II. EXPERIMENT

Single crystals of $(La_{0.4}Pr_{0.6})_{1.2}Sr_{1.8}Mn_2O_7$ were grown by the oating zone method using a mirror furnace. The calculated lattice parameters were shown in a previous report⁹. The dimensions of the z=0.6 sample are 3.4 3 mm² in the ab-plane and 1mm along the c-axis. M agnetoresistance was measured by means of a conventional four-probe technique at the T sukuba M agnet Laboratory, the N ational Institute for M aterials Science and at the High Field Laboratory for Superconducting Materials, Institute for M aterials R esearch, Tohoku U niversity. M agnetostriction measurements were performed using a strain gauge method¹⁶. The magnetization measurements were made using a superconducting quantum interference device magnetometer at Iwate University.

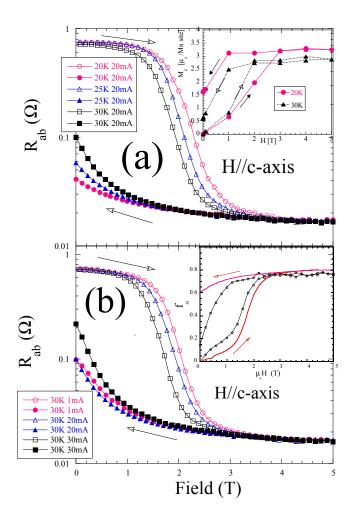


FIG. 2: Magnetoresistance data R_{ab} of a (La_{0:4} Pr_{0:6})_{1:2}Sr_{1:8}M n₂O₇ single crystal in a eld applied along the caxis, (a) at T = 20,25 and 30 K for I = 20 m A and (b) at I = 1,20 and 30 m A for 30 K. The inset of (a) shows the eld dependence of the magnetization along the caxis at both 20 and 30 K. In the inset of (b), a solid curve represents the volume fraction of metalphase $f_{\rm M}$ estimated from the R (H) data using an elective medium approximation discussed in the text. For comparison, the normalized magnetization curve M (H) /M full at 30K is also presented.

III. RESULTS AND DISCUSSION

Let us show in Fig 2 the magnetoresistance data R_{ab} of (La_{0:4}, Pr_{0:6})_{1:2}Sr_{1:8}M n₂O₇ single crystal at selected temperatures. Firstly, a eld-induced insulator to metal transition and its associated CMR expectation expected around 2T, accompanied by a huge decrease in resistance by about two-orders of magnitude. Secondly, a clear hysteresis in R_{ab} is seen even though applied elds are lowered down to zero. As mentioned above, the system still remains in a metastable state just after the external eld

is switched o . In Fig 2 (a), it can be seen that the characteristic eld which switches the sample state from PM I to FMM, depends upon temperature and increases from 1.8T at 30K to 2.2T at 20K, in a good agreement with the magnetization curves in the inset of Fig 2 (a). Moreover, such a critical eld is also controlled by changing an applied current (Fig.2 (b)) A local pule heating assists a jump over potential barriers of local free energy allowing them to shift from PM I towards FM M states at num erous PM I clusters within the sample, resulting in a suppression in both the switching eld and hysteresis e ect. Here, we estimate a volume fraction of metal (or insulator) from the R (H) data using an e ective medium approximation (EMA) 18,19. In our calculation, we assum e a two-com ponent com posite m aterial m ade up of both metallic and insulating grains with their resistivities, M and I, giving an elective resistivity E for spherical shape as follow s;

$$f_{M} = \frac{e}{e + 2_{M}} + (1 - f_{M}) = \frac{I}{e + 2_{I}} = 0$$
 (1)

, where f_M denotes a volume fraction of metal with m etallic resistivity $_{\mathrm{M}}$. Substituting the R (H) data into the above equation and solving it with respect to f_{M} , we get a volume fraction of metal as shown in the inset of Fig 2 (b). For comparison, the magnetization curve at 30K is also presented. The calculated curve based on the EMA roughly reproduces the M (H) curve except for the low - eld region in the dem agnetization process. The di erence in M (H) and f_M is probably related to the form ation of magnetic domains conserving ferromagnetic m om ents 20 . Here, I is taken as the value of R just before application of the $\,$ eld and $_{M}$ is determined from the value of R (H) at a maximum eld of 5T. Furtherm ore, a volum e fraction of metallic cluster at 5T is assumed to be equal to the ration M $(5T)/M_{full}$ = 0.8, in which M full m eans the value of full m agnetization corresponding to the magnetic moment of the M n ion (= 3.4) B at a hole content x=0.4). A coording to a previous work on cubic manganites by Jaim e et al. 21, assuming both ferrom agnetic and electronic free energy functionals and m in im izing the total free energy, they obtain one solution where the rst order parameter m (= M (H;T) /M_{full}) is proportional to the second order param eter $c \in f_M$). Thus, it is reasonable to take the preceding assumption in the EMA.

Now, we exam ine the resistive relaxation data as a function of tem perature and excited current as depicted in Fig.3 (a) and (b). The system starts from a metastable state of the coexistence between metallic and insulating regions when a eld is turned o , and should come back to a stable insulator at the original ground-state after a very long time. At 30K, the value of R $_{\rm ab}$ with I = 30 m A rapidly relaxes within a few hundred seconds and then restores the ground-state value, as shown in Fig.3. The relaxation time of remanent R $_{\rm ab}$ is elongated at least by two orders of magnitude upon decreasing temperature from 30 K down to 20K. We have noted from previous studies

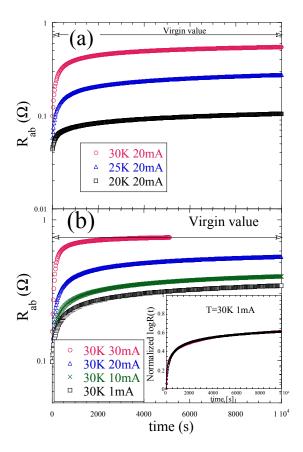


FIG. 3: Resistive relaxation pro les of a $(La_{0.4}Pr_{0.6})_{1.2}Sr_{1.8}Mn_2O_7$ single crystal as a function of (a)tem perature and (b) current. (a) I= 1,10,20 and 30m A at 30K, (b) T=20,25 and 30K at I=30m A. The inset of (b) represents a typical curve tted to normalized R (t) data at 30K with I=1mA, using a stretched exponential function with the characteristic relaxation time and exponent, and respectively. We have =1.1 10^4 s and =0.25.

that a relaxation curve in both rem anent m agnetization and lattice striction in a (La $_{0.4}$ P r $_{0.6}$) $_{1.2}$ Sr $_{1.8}$ M n $_{2}$ O $_{7}$ single crystal is well—tted using a stretched exponential function with the characteristic relaxation time and exponent, and . A deviation in exponent from = 1 indicates the existence ofmultiple relaxation processes in the observed slow dynam ics. In a similar way, we try to exam ine a temporal prometer anent magnetoresistance following a stretched exponential from such as normalized logR (t) = [logR (t) logR (0)]=[logR (1) logR (0)]=1-exp[(t=)], where R (1) and R (0) denote the virgin and initial values, before application of the eld and just after removal of the eld, respectively. A typical curve tted to normalized R (t) data at 30K with I=1m A is presented in the inset of Fig.3 (b).

As a result, the $\,$ tted param eters $_R$ and $\,$ are plotted as a function of tem perature, as shown in Fig. 4. For com parison, the previous relaxation param eters, $_M$ and $_L$, for both m agnetization and m agnetostriction curves are also given. Firstly, upon decreasing the applied cur-

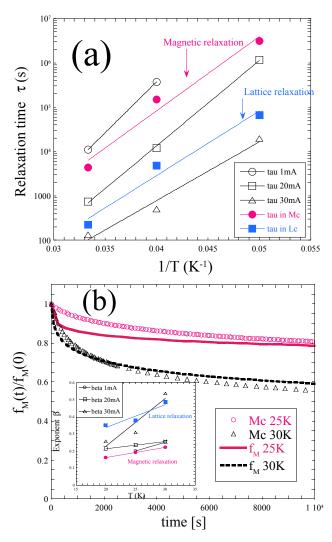


FIG. 4: (a) The resistive relaxation time $_{\rm R}$ as a function of 1=T for I= 1,20 and 30 mA. For comparison, both the magnetic and lattice relaxation parameters, $_{\rm M}$ and $_{\rm L}$, are also given.(b) A relaxation pro le of the metallic fraction $f_{\rm M}$ estimated from the R (t) data using the EMA model. Solid and dashed curves represent calculation data at 25 and 30 K, respectively. The normalized caxis magnetization data, M $_{\rm C}$ (t)=M $_{\rm C}$ (0), are given. In the inset of (b), the exponent in the resistive, magnetic and lattice relaxations is plotted as a function of temperature.

rent, the value of $_{\rm R}$ tends to approach the magnetic relaxation time , $_{\rm M}$. This tendency is also observed in the temperature variation of exponent , as shown in the inset of Fig.4 (b). On the other hand, the value of $_{\rm L}$ is smaller by about two orders of magnitude than the lifetime of R (t) and M (t). Secondly, the relaxation time in R (t);M (t) and L (t) follows the thermally activated T-dependence, = $_{\rm 0} \exp{\rm (=kT)}$, where denotes the activation energy corresponding to the potential barrier between the metastable FMM state and the local maximum in free energy. $_{\rm 0}$ represents the intrinsic re-

laxation time determined from microscopic mechanism. The activation energy of R (t), $_{\rm R}$ varies from 305 K at I = 30m A, through 443K at I = 20m A, up to 530 K at I=1mA. These values are not far from the activation energies of both rem anent lattice and m agnetization, $_{\rm L}$ = 335 K and $_{\rm M}$ = 386 K . The resistive and magnetic relaxations are taken as signatures of the phase transition from metastable FMM to stable PMI states in the long time scale. On the other hand, the lattice relaxation is not due to the structural transition associated with cooperative phenom ena but arises from a local lattice distortion of M nO 6 octahedra without a long-range order. In Fig.4 (b), a temporal prole of the metallic fraction f_M estimated from the R (t) data for I = 1 m A using the EM A model is given. We notice that calculated curves of the m etallic fraction tend to approach the m agnetization data after a long period of time. This nding seem s to be reasonable if we assume that a ferrom agnetic order param eter, m, is proportional to an electronic one, f_M . The di erence in the initial drop between the metallic fraction and the magnetization curves is probably related to the form ation of FMM domains might responsible for the disagreem ent observed between f_M and the normalized magnetization as depicted in the inset of Fig 2 (b).

Finally, we explore resistive relaxation data as a function of eld at selected temperatures, as shown in Fig.5. The value of the relaxation time grows exponentially upon increasing the applied eld because a local minimum in the free energy of the metastable state is stabilized by lowering the m in im um free energy by $_{\rm eff}$ $_{\rm 0}{\rm H}$. eld dependence of (H), is well tted by such a functional form as $_{R}$ (0)exp($_{\mathrm{eff}}$ 0H/kT). The e ective m agnetic m om ent $_{\rm eff}$ is expressed as $_{\rm eff}$ = N g $_{\rm B}$ S , giving the average number of the M n ions, N, contributing to the relaxation process of the FM M to PM I transition at the level of clusters in divided subsystem s11. Here, S represents the average spin number at the M n ion site and we set S = 1.8 at a hole concentration of 0.4. A characteristic size of FM M clusters is estimated from the relaxation data using the exponential functional form to be N $_{\rm R}$ = 140 at 30 K (N $_{\rm R}$ = 166 at 25K). M oreover, from m agnetic (H) we get N $_{\rm M}$ = 122 at 30 K sim ilar to the value of N $_{\rm R}\,$. If the average distance between adjacent M n ions is taken as 4 A, the cluster size of the FM M $\,$ region reaches several tens of nanom eter. On the other hand, $_{\rm L}$ is independent of eld up to 0.5T and shows no outstanding variation, in contrast with the value of both $_{\rm R}$ (H) and $_{\rm M}$ (H). This indicates that magnetostriction phenomena are not always associated with a long-rang order param eter although magnetization and m agnetotransport are closely related to it.

In sum mary, we have shown that the eld-induced insulator to metal transition observed in the single crystal of $(La_{0.4}Pr_{0.6})_{1.2}Sr_{1.8}Mn_2O_7$ is accompanied by a resistive relaxation process. The temporal proles observed in remanent resistance follow a stretched exponential function accompanied by a slow relaxation similar to those exhibited by magnetization and magnetostriction. We

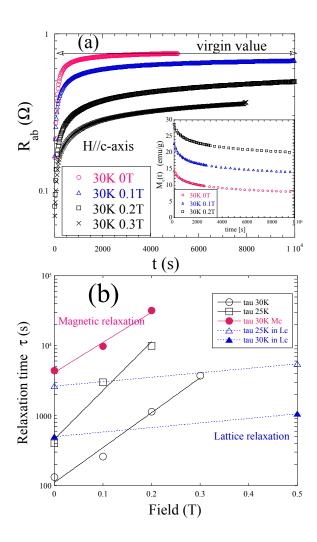


FIG. 5: (a) Resistive relaxation pro les of a (La $_{0.4}$ Pr $_{0.6}$) $_{1.2}$ Sr $_{1.8}$ M n $_{2}$ O $_{7}$ single crystal as a function of eld. H = 0,0.1,0.2 and 0.3 T at 30K with I= 30m A. In the inset of (a), magnetic relaxation data are also shown at 30K. (b) The resistive relaxation time $_{R}$ (H) as a function of eld at 25 and 30K with I= 30 m A. For comparison, the magnetic and lattice relaxation times, $_{M}$ (H) and $_{L}$ (H), are also given at selected temperatures.

dem onstrate that the rem anent relaxation in magnetotransport has a close relationship with the magnetic relaxation that can be understood in the fram ework of an e ective medium approximation assuming a proportionality between the rst order parameter and the second order one.

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